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LIST OF REFERENCES CITED BY APPLICANTYS (Use several sheets if necessary)		A	FILING DATE March 26, 2004		GROUP 1751		
			.S. PATENT DOCUMENTS				
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
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	ОТ	HER DOCUMENT(S)	(Including Author, Title, Date, Pertine	nt Pages, Etc.)			
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EXAMINER MAK			DATE CONSIDERED	DATE CONSIDERED 11/6/07			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet_1_ of _1_